

Portable device

According to §15.247(e)(i) and §1.1307(b)(1), systems operating under the provisions of this section shall be operated in a manner that ensures that the public is not exposed to radio frequency energy level in excess of the Commission's guidelines.

According to KDB447498 D01 General RF Exposure Guidance V06

The 1-g SAR and 10-g SAR test exclusion thresholds for 100 MHz to 6 GHz at test separation distances ≤ 50 mm are determined by:

$[(\text{max. power of channel, including tune-up tolerance, mW}) / (\text{min. test separation distance, mm})] \cdot \sqrt{f(\text{GHz})} \leq 3.0$ for 1-g SAR and ≤ 7.5 for 10-g extremity SAR, where:

- $f(\text{GHz})$ is the RF channel transmit frequency in GHz
- Power and distance are rounded to the nearest mW and mm before calculation
- The result is rounded to one decimal place for comparison

When the minimum test separation distance is < 5 mm, a distance of 5 mm is applied to determine SAR test exclusion.

BT:

Modulation	Channel Freq. (GHz)	Conducted power (dBm)	Conducted power (mW)	Tune-up power (dBm)	Max tune-up power (dBm)	Max tune-up power (mW)	Distance (mm)	Result calculation	SAR Exclusion threshold	SAR test exclusion
GFSK	2.402	-5.21	0.30	-4.5±1	-3.5	0.45	<5	0.13846	3.00	YES
	2.441	-4.58	0.35	-4.5±1	-3.5	0.45	<5	0.13958	3.00	YES
	2.480	-4.42	0.36	-4.5±1	-3.5	0.45	<5	0.14069	3.00	YES
π/4-DQPSK	2.402	-5.83	0.26	-5±1	-4	0.40	<5	0.12340	3.00	YES
	2.441	-5.17	0.30	-5±1	-4	0.40	<5	0.12440	3.00	YES
	2.480	-5.28	0.30	-5±1	-4	0.40	<5	0.12539	3.00	YES
8DPSK	2.402	-5.70	0.27	-4.7±1	-3.7	0.43	<5	0.13223	3.00	YES
	2.441	-4.83	0.33	-4.7±1	-3.7	0.43	<5	0.13330	3.00	YES
	2.480	-4.77	0.33	-4.7±1	-3.7	0.43	<5	0.13436	3.00	YES
BLE	2.402	-3.32	0.47	-3±1	-2	0.63	<5	0.19558	3.00	YES
	2.440	-3.21	0.48	-3±1	-2	0.63	<5	0.19712	3.00	YES
	2.480	-2.08	0.62	-3±1	-2	0.63	<5	0.19873	3.00	YES

Conclusion:

For the max result : 0.19873W/Kg ≤ 3.0 for 1g SAR, No SAR is required.

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Signature:

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